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Application/Control No.	Applicant(s)/Patent under Reexamination	
09/943,780	BAKER ET AL.	
Examiner	Art Unit	
David J. Blanchard	1643	

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Class	Subclass	Date	Examiner
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Class	Subclass	Date	Examiner
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SEQ IC	NO:69	1/25/2007	DB

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STIC search SEQ ID NO:69 (SCORE results in related USSN 10/677,669)	1/25/2007	DB
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